

FORM 1449 OCT 30 2003 TRADEMARK OFFICE	INFORMATION DISCLOSURE STATEMENT		Docket Number: 9997.69US01	Application Number: 10/613,260
	IN AN APPLICATION		Applicant: MANHAEVE et al.	
	(Use several sheets if necessary)		Filing Date: 3 July 2003	Group Art Unit: 2899-2829

U.S. PATENT DOCUMENTS						
EXAMINER INITIAL	DOCUMENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
/	5 818 268	6 Oct. 1998	KIM et al.			/
/	6 414 511 B1	2 July 2002	JANSSEN et al.			/
/	5 914 615	22 June 1999	CHESS			/
/	5 483 170	9 Jan. 1996	BEASLEY et al.			/

  

FOREIGN PATENT DOCUMENTS							
	DOCUMENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
/	EP 0 811 850	✓ 10 Dec. 1997	EPO			/	/
/	EP 0 386 804	✓ 12 Sept. 1990	EPO			/	/
/	EP 0 672 911	✓ 20 Sept. 1995	EPO			/	/
/	WO 98/15844	✓ 16 April 1998	WIPO			/	/
/	EP 1 107 013	✓ 13 June 2001	EPO			/	/

  

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)		
/	✓	STRAKA et al. "A fully digital controlled off-chip I <sub>q</sub> measurement unit". Automation and Test in Europe, 1998. Proceedings Paris, France, Feb. 1998, Los Alamitos, CA, IEEE Comput. Soc. US, pp. 495-500 (23 Feb. 1998).
/	✓	SU et al. "Transient power supply current monitoring-a new test method for CMOS VLSI circuits". Journal of Electronic Testing: Theory and Applications, Vol. 6, No. 1, pp. 23-43 (1995).
/	✓	EICHENBERGER et al. "On Charge Injection in Analog MOS Switches and Dummy Switch Compensation Techniques". IEEE Transactions on Circuits and Systems, Vol. 37, No. 2, pp. 256-264 (Feb. 1990).
/	✓	EICHENBERGER et al. "Dummy Transistor Compensation of Analog MOS Switches". IEEE Journal of Solid-State Circuits, Vol. 24, No. 4, pp. 1143-1146 (August 1989).

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EXAMINER	<i>Panda</i>	DATE CONSIDERED	12/06/04
EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form for next communication to the Applicant.			